Attorney's Docket No.: 13906-157001 / 2003P00945 US01

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Wu et al. Art Unit: 2114

Serial No.: 10/814,836 Examiner: Paul F. Contino

Filed: March 31, 2004 Conf. No.: 6482

Title : FAILURES OF COMPUTER SYSTEM DIAGNOSTIC PROCEDURES

ADDRESSED IN SPECIFIED ORDER

## **MAIL STOP AF**

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed after a final Office action or a Notice of Allowance, but before payment of the issue fee. Please apply the \$180 in payment of the late submission fee of \$1.17(p) and any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 13906-157001	Application No. 10/814,836	
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CER \$1 98(b))		Applicant Wu et al.		
		Filing Date March 31, 2004	Group Art Unit 2114	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,029,004	02/22/2000	Bortnikov et al.			
	AB	6,173,440	01/09/2001	Darty			
	AC	6,381,739	04/30/2002	Breternitz, Jr. et al			
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	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Translation	
Initial	ID _	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO			-				
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)				
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	AQ			
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with					
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